

Search Notes

Application/Control No.

10/601,872

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

CHOI ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	27	2/14/2006	DWY
429	40	2/14/2006	DWY
429	42	2/14/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/14/2006	DWY